

# PX Scanner In-Situ X-ray Diffraction: Initial Results

## Application Note

X-ray Crystallography



The PX Scanner is a revolutionary product from Agilent Technologies which has been designed specifically for the *in-situ* identification and analysis of protein crystals within multi-well crystallisation plates.

Within this application note we present a collection of experimental results obtained using the PX Scanner.

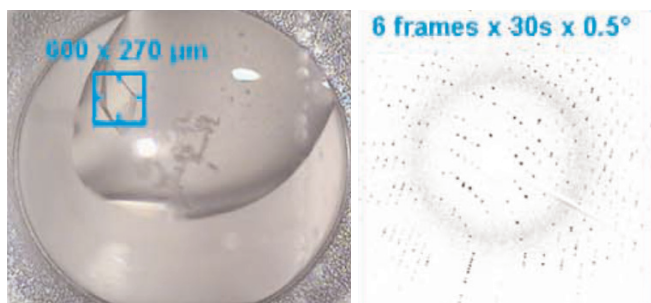


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## Model Protein Benchmarks

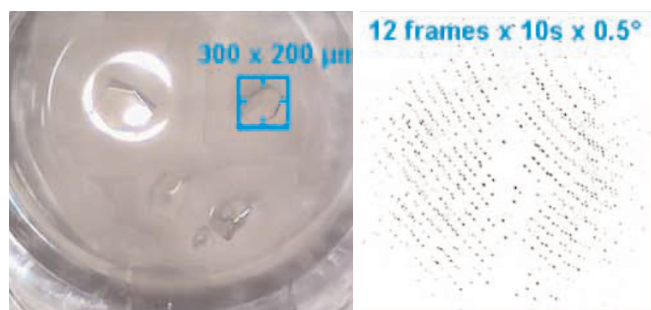
### Thaumatococcus

- Strong diffraction to 2.0 Å using 30 second frames
- Easily indexed: Tetragonal form:  $a = 58.6 \text{ Å}$   $c = 151.9 \text{ Å}$



### Lysozyme

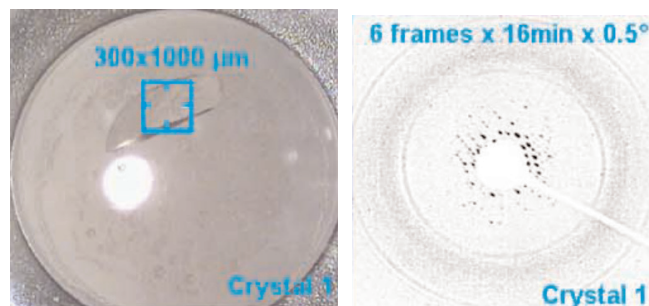
- Strong diffraction to 2.0 Å using 10 second frames
- Easily indexed: Tetragonal form:  $a = 78.9 \text{ Å}$   $c = 38.7 \text{ Å}$



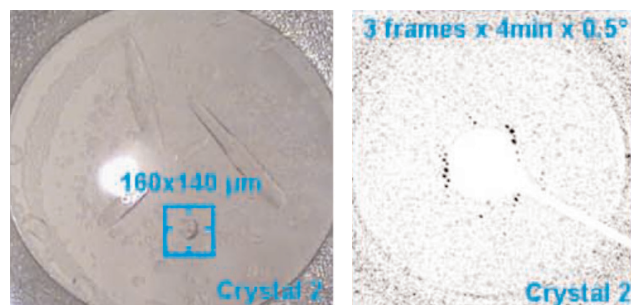
### Intrinsic Membrane Protein (Imperial College London)

Intrinsic membrane protein crystals generally give weak, low resolution diffraction. The crystals studied here may grow up to 1mm long, and diffract to 8 Å on average at the synchrotron. The PX Scanner gave the following results:

	Angular resolution (Å)
Crystal 1	9 Å
Crystal 2	11 Å

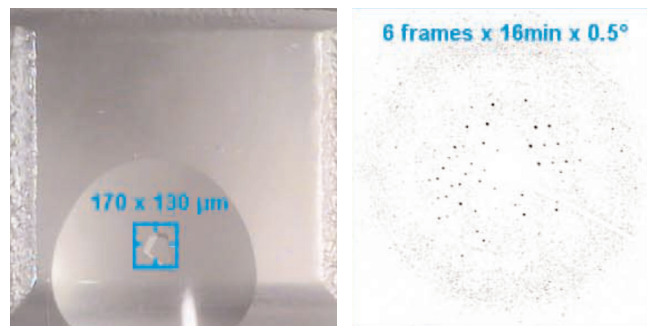


Surprisingly it was possible to detect protein diffraction, even with crystals of less than 200 μm length. These results indicate that the PX scanner is a useful tool for screening small crystals of challenging proteins.



### A Typical Weakly Diffracting Protein (Laboratory of Molecular Biophysics, Oxford University)

A more typical example of a weakly diffracting crystal than the membrane protein, is that of the soluble protein provided by a group at the Laboratory of Molecular Biophysics at Oxford University. This protein was found to diffract to 4.5 Å on the PX Scanner using 16 min exposures compared to 4 Å when measured at the synchrotron.



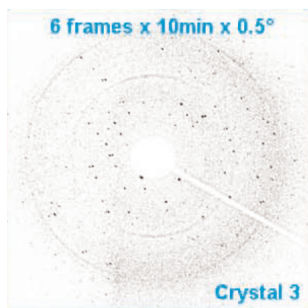
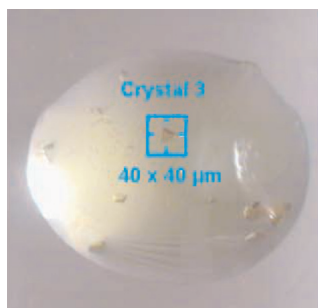
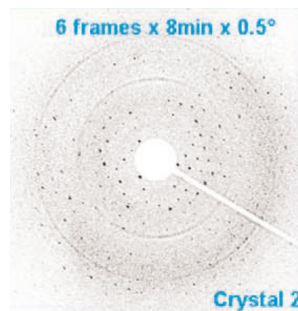
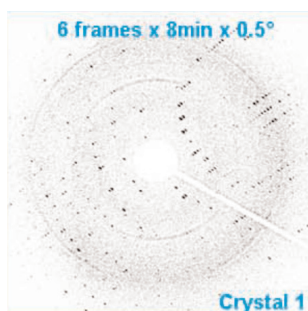
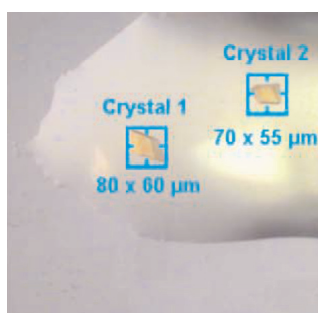
## Protein Kinase – Crystal Comparison (GlaxoSmithKline, Stevenage)

The PX Scanner allows crystal diffraction properties to be assessed *in-situ*. This allows comparison and ranking of a set of crystals within a crystallisation plate. In this example:

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Crystal 1	2.7 Å
Crystal 2	3.2 Å
Crystal 3	3.5 Å

The identical trigonal cell was indexed for each crystal



Indicates the crystal x-rayed

## For More Information

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